

RoHS Compliant Product  
A suffix of "-C" specifies halogen and lead-free

## DESCRIPTION

The SDT3585S-C is the highest performance trench N+P MOSFETs with extreme high cell density, which provide excellent  $R_{DS(ON)}$  and gate charge for most of the synchronous buck converter applications.

The SDT3585S-C meet the RoHS and Green Product requirement with full function reliability approved.

## APPLICATIONS

- Power Management In Note Book
- Portable Equipment
- DC/DC Converter
- Load Switch

## MARKING

3585S

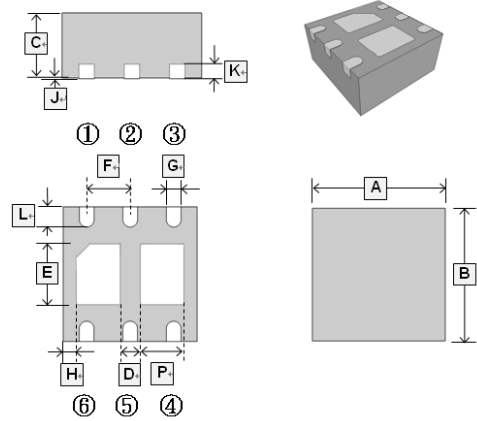
## PACKAGE INFORMATION

Package	MPQ	Leader Size
DFN2x2-6L-J	3K	7 inch

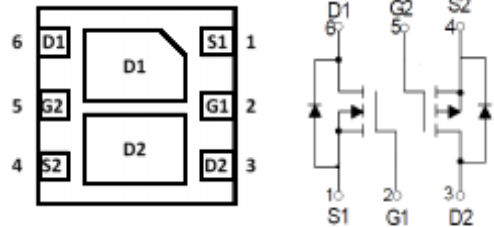
## ORDER INFORMATION

Part Number	Type
SDT3585S-C	Lead (Pb)-free and Halogen-free

### DFN2x2-6L-J



REF.	Millimeter		REF.	Millimeter	
	Min.	Max.		Min.	Max.
A	1.90	2.10	G	0.25	0.35
B	1.90	2.10	H	0.20 BSC.	
C	0.675	0.80	J	-	0.06
D	0.25	0.35	K	0.15	0.25
E	0.75	1.10	L	0.20	0.38
F	0.65 TYP.		P	0.52	0.72



## ABSOLUTE MAXIMUM RATINGS ( $T_A=25^\circ\text{C}$ unless otherwise specified)

Parameter	Symbol	Rating		Unit	
		N-ch	P-ch		
Drain-Source Voltage	$V_{DS}$	20	-20	V	
Gate-Source Voltage	$V_{GS}$	$\pm 12$	$\pm 12$	V	
Continuous Drain Current <sup>1</sup> @ $V_{GS}=4.5V$	$I_D$	$T_A=25^\circ\text{C}$	5	-3.5	A
		$T_A=70^\circ\text{C}$	4	-2.8	
Pulsed Drain Current <sup>3</sup>	$I_{DM}$	17	-12	A	
Total Power Dissipation	$P_D$	$T_A=25^\circ\text{C}$ 1.5		W	
Operating Junction & Storage Temperature Range	$T_J, T_{STG}$	-55~150		$^\circ\text{C}$	
Thermal Data					
Maximum Thermal Resistance from Junction-Ambient <sup>1</sup>	$R_{\theta JA}$	$t \leq 5\text{sec}, 83$		$^\circ\text{C/W}$	
		Steady State, 125			
Maximum Thermal Resistance from Junction-Ambient <sup>2</sup>		250			
Maximum Thermal Resistance from Junction-Case <sup>1</sup>	$R_{\theta JC}$	8.4			

**N-CH ELECTRICAL CHARACTERISTICS** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Drain-Source Breakdown Voltage	$BV_{DSS}$	20	-	-	V	$V_{GS}=0, I_D=250\mu\text{A}$
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_J$	-	0.018	-	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D=1\text{mA}$
Gate-Threshold Voltage	$V_{GS(th)}$	0.5	-	1.2	V	$V_{DS}=V_{GS}, I_D=250\mu\text{A}$
Forward Transfer conductance	$g_{fs}$	-	20	-	S	$V_{DS}=5\text{V}, I_D=4\text{A}$
Gate-Body Leakage Current	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{DS}=0, V_{GS}=\pm 12\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	1	$\mu\text{A}$	$V_{DS}=16\text{V}, V_{GS}=0, T_J=25^\circ\text{C}$
		-	-	5		$V_{DS}=16\text{V}, V_{GS}=0, T_J=55^\circ\text{C}$
Drain-Source On-Resistance <sup>4</sup>	$R_{DS(ON)}$	-	-	37	m $\Omega$	$V_{GS}=4.5\text{V}, I_D=4\text{A}$
		-	-	45		$V_{GS}=2.5\text{V}, I_D=3\text{A}$
Total Gate Charge	$Q_g$	-	8.6	-	nC	$V_{DS}=15\text{V}$ $V_{GS}=4.5\text{V}$ $I_D=4\text{A}$
Gate-Source Charge	$Q_{gs}$	-	1.37	-		
Gate-Drain Charge	$Q_{gd}$	-	2.3	-		
Turn-On Delay Time	$T_{d(on)}$	-	5.2	-	nS	$V_{DS}=10\text{V}$ $V_{GS}=4.5\text{V}$ $I_D=4\text{A}$ $R_G=3.3\Omega$ $R_D=2.5\Omega$
Rise Time	$T_r$	-	34	-		
Turn-Off Delay Time	$T_{d(off)}$	-	23	-		
Fall Time	$T_f$	-	9.2	-		
Input Capacitance	$C_{iss}$	-	635	-	pF	$V_{DS}=15\text{V}$ $V_{GS}=0$ $f=1\text{MHz}$
Output Capacitance	$C_{oss}$	-	70	-		
Reverse Transfer Capacitance	$C_{rss}$	-	63	-		
<b>Source-Drain Diode</b>						
Continuous Source Current <sup>1</sup>	$I_S$	-	-	5	A	
Pulsed Source Current <sup>3</sup>	$I_{SM}$	-	-	17	A	
Forward On Voltage <sup>4</sup>	$V_{SD}$	-	0.7	1.2	V	$I_S=1\text{A}, V_{GS}=0\text{V}$
Reverse Recovery Time	$T_{rr}$	-	7.5	-	nS	$I_S=4\text{A}, V_{GS}=0\text{V},$ $di/dt=100\text{A}/\mu\text{s}$
Reverse Recovery Charge	$Q_{rr}$	-	2.1	-	nC	

Notes:

- Surface mounted on a 1 inch<sup>2</sup> FR-4 board with 2oz copper.
- Surface mounted on FR-4 Board using the minimum recommended pad size.
- Pulse width limited by maximum junction temperature.
- The data tested by pulsed, pulse width  $\leq 300\mu\text{s}$ , duty cycle  $\leq 2\%$ .

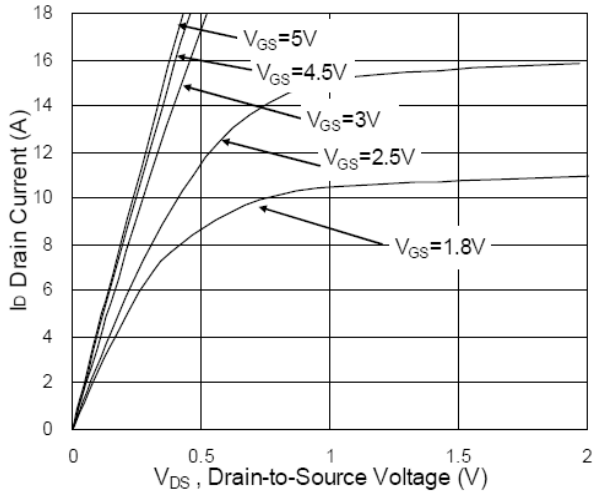
**P-CH ELECTRICAL CHARACTERISTICS** ( $T_J=25^\circ\text{C}$  unless otherwise specified)

Parameter	Symbol	Min.	Typ.	Max.	Unit	Test Condition
Drain-Source Breakdown Voltage	$BV_{DSS}$	-20	-	-	V	$V_{GS}=0, I_D = -250\mu\text{A}$
Breakdown Voltage Temperature Coefficient	$\Delta BV_{DSS}/\Delta T_J$	-	-0.01	-	V/ $^\circ\text{C}$	Reference to $25^\circ\text{C}$ , $I_D = -1\text{mA}$
Gate-Threshold Voltage	$V_{GS(th)}$	-0.5	-	-1.2	V	$V_{DS}=V_{GS}, I_D = -250\mu\text{A}$
Forward Transfer conductance	$g_{fs}$	-	9	-	S	$V_{DS} = -5\text{V}, I_D = -3\text{A}$
Gate-Body Leakage Current	$I_{GSS}$	-	-	$\pm 100$	nA	$V_{DS}=0, V_{GS} = \pm 12\text{V}$
Zero Gate Voltage Drain Current	$I_{DSS}$	-	-	-1	$\mu\text{A}$	$V_{DS} = -16\text{V}, V_{GS}=0, T_J=25^\circ\text{C}$
		-	-	-5		$V_{DS} = -16\text{V}, V_{GS}=0, T_J=55^\circ\text{C}$
Drain-Source On-Resistance <sup>4</sup>	$R_{DS(ON)}$	-	-	75	m $\Omega$	$V_{GS} = -4.5\text{V}, I_D = -3\text{A}$
		-	-	105		$V_{GS} = -2.5\text{V}, I_D = -2\text{A}$
Total Gate Charge	$Q_g$	-	9.7	-	nC	$V_{DS} = -15\text{V}$ $V_{GS} = -4.5\text{V}$ $I_D = -3\text{A}$
Gate-Source Charge	$Q_{gs}$	-	2.05	-		
Gate-Drain Charge	$Q_{gd}$	-	2.43	-		
Turn-On Delay Time	$T_{d(on)}$	-	4.8	-	nS	$V_{DS} = -10\text{V}$ $V_{GS} = -4.5\text{V}$ $I_D = -3\text{A}$ $R_G=3.3\Omega$ $R_D=3.33\Omega$
Rise Time	$T_r$	-	9.6	-		
Turn-Off Delay Time	$T_{d(off)}$	-	52	-		
Fall Time	$T_f$	-	8.4	-		
Input Capacitance	$C_{iss}$	-	686	-	pF	$V_{DS} = -15\text{V}$ $V_{GS}=0$ $f=1\text{MHz}$
Output Capacitance	$C_{oss}$	-	90.8	-		
Reverse Transfer Capacitance	$C_{rss}$	-	80.4	-		
<b>Source-Drain Diode</b>						
Continuous Source Current <sup>1</sup>	$I_S$			-3.5	A	
Pulsed Source Current <sup>3</sup>	$I_{SM}$			-12	A	
Forward On Voltage <sup>4</sup>	$V_{SD}$		-0.7	-1.2	V	$I_S = -1\text{A}, V_{GS}=0\text{V}$
Reverse Recovery Time	$T_{rr}$	-	8.4	-	nS	$I_S = -3\text{A}, V_{GS}=0\text{V},$ $di/dt=100\text{A}/\mu\text{s}$
Reverse Recovery Charge	$Q_{rr}$	-	3.3	-	nC	

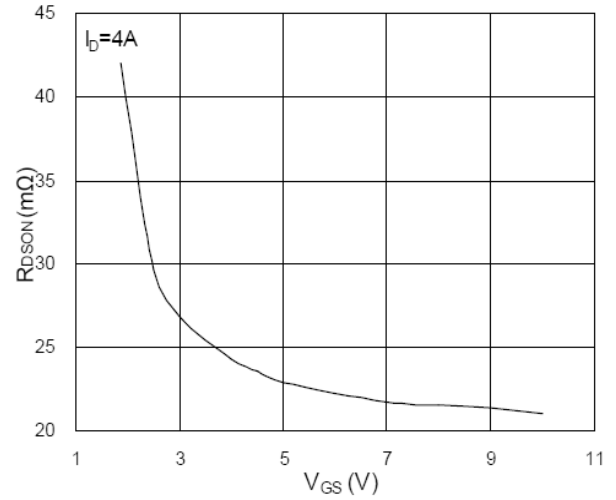
Notes:

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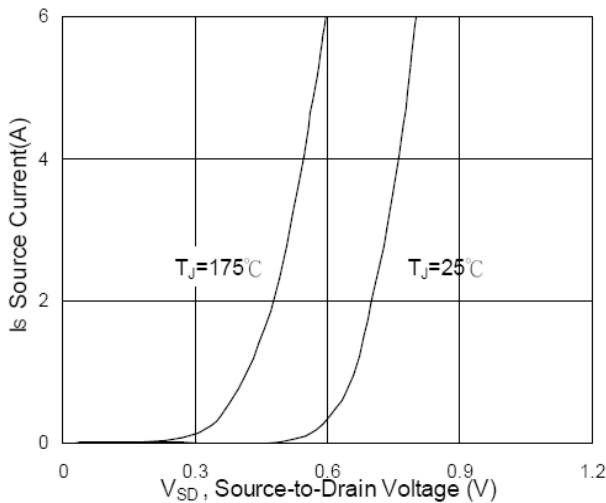
**N-CH CHARACTERISTIC CURVE**



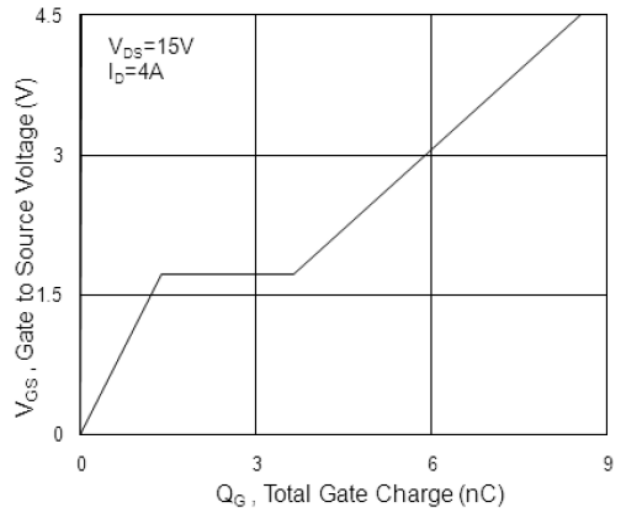
**Fig.1 Typical Output Characteristics**



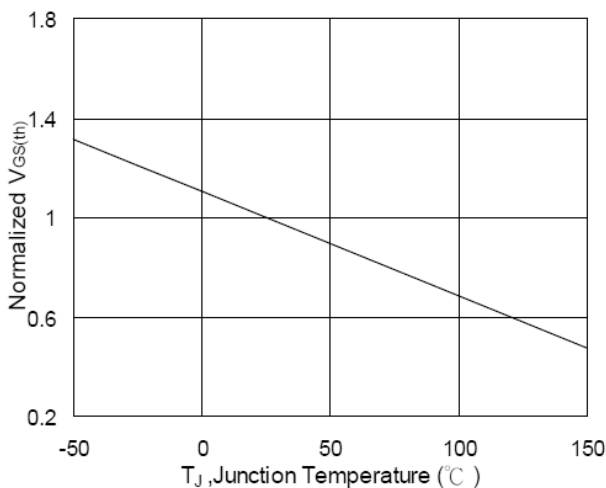
**Fig.2 On-Resistance vs. Gate-Source**



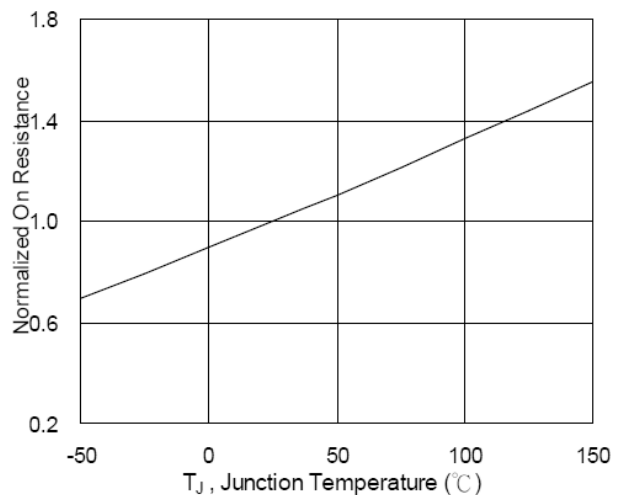
**Fig.3 Forward Characteristics Of Reverse**



**Fig.4 Gate-Charge Characteristics**

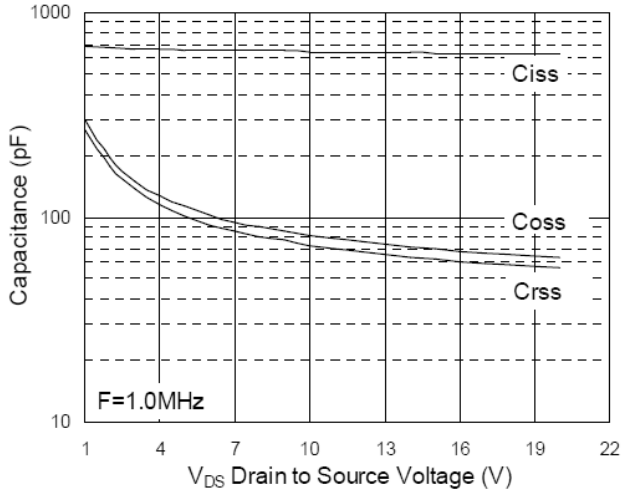


**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**

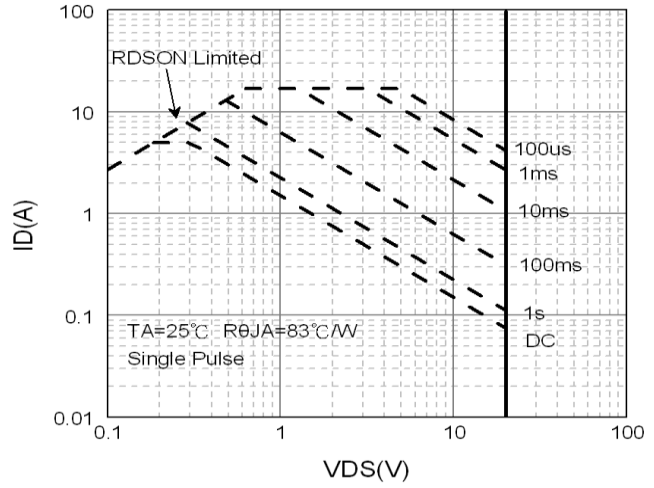


**Fig.6 Normalized  $R_{DS(ON)}$  vs.  $T_J$**

**N-CH CHARACTERISTIC CURVE**

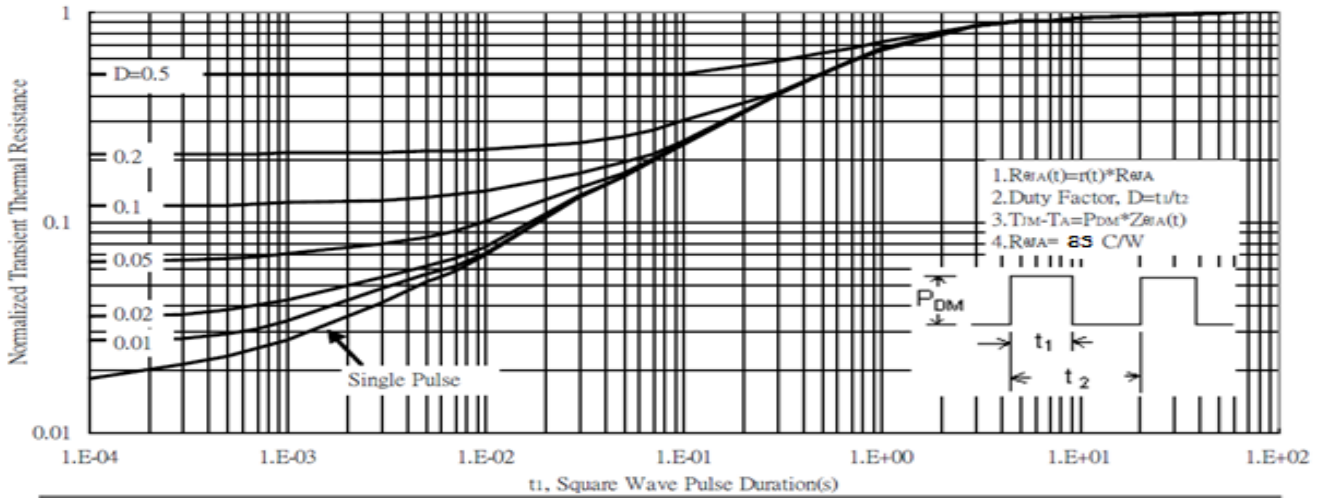


**Fig.7 Capacitance**

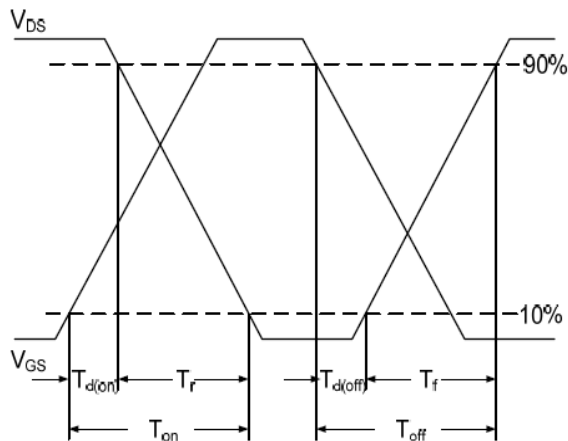


**Fig.8 Safe Operating Area**

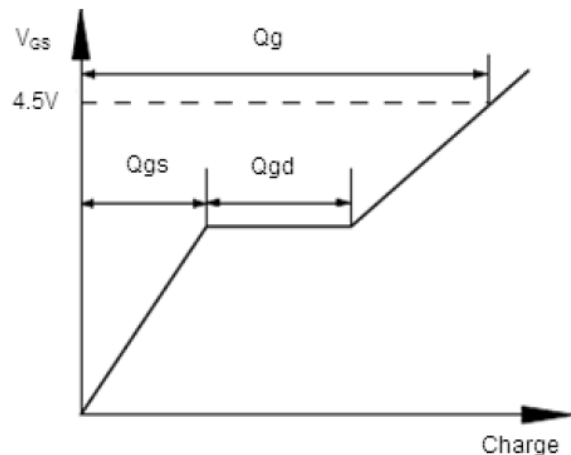
**Transient Thermal Response Curves**



**Fig.9 Normalized Maximum Transient Thermal Impedance**

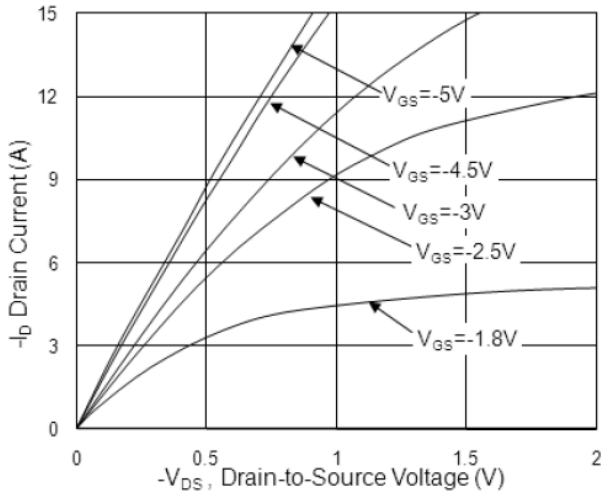


**Fig.10 Switching Time Waveform**

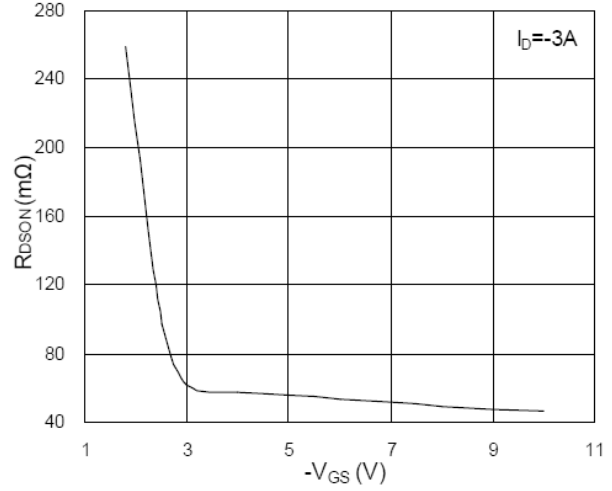


**Fig.11 Gate Charge Waveform**

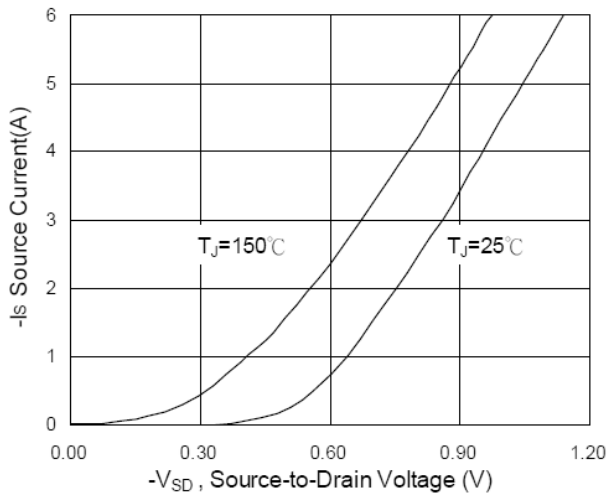
**P-CH CHARACTERISTIC CURVE**



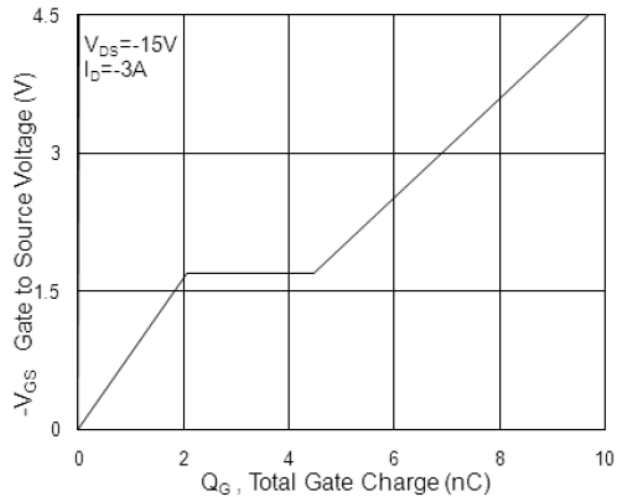
**Fig.1 Typical Output Characteristics**



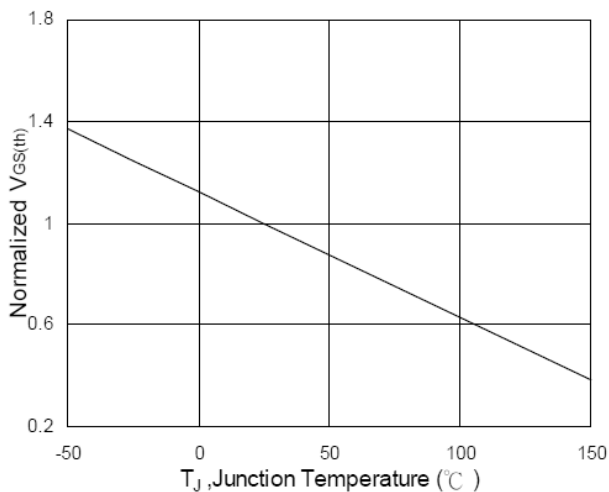
**Fig.2 On-Resistance vs. Gate-Source**



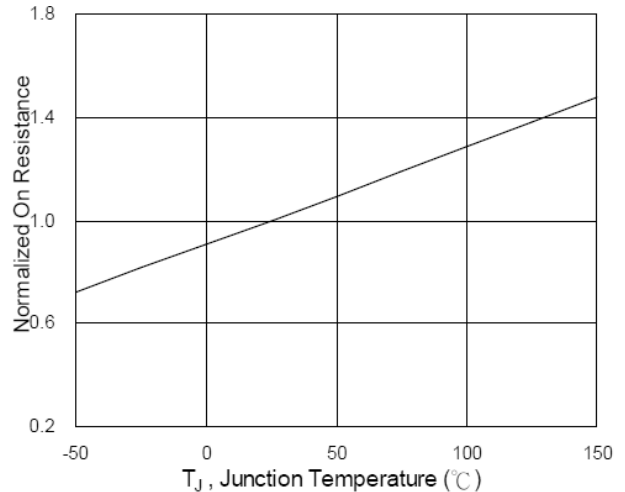
**Fig.3 Forward Characteristics Of Reverse**



**Fig.4 Gate-Charge Characteristics**



**Fig.5 Normalized  $V_{GS(th)}$  vs.  $T_J$**



**Fig.6 Normalized  $R_{DS(ON)}$  vs.  $T_J$**

**P-CH CHARACTERISTIC CURVE**

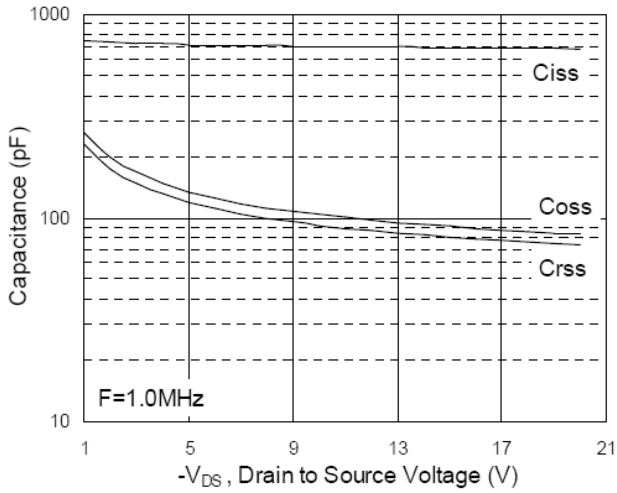


Fig.7 Capacitance

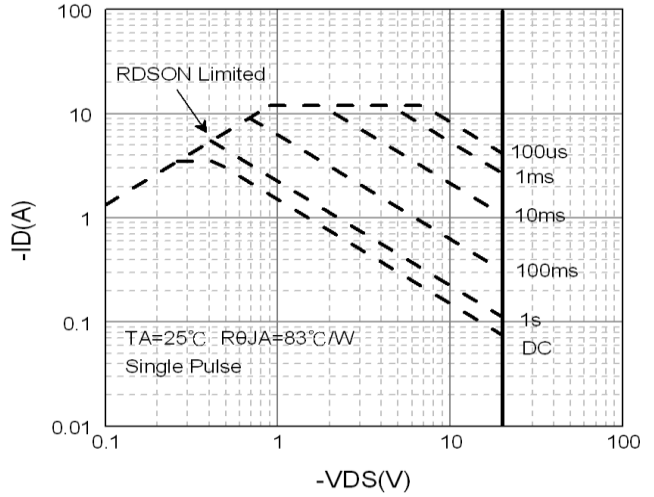


Fig.8 Safe Operating Area

**Transient Thermal Response Curves**

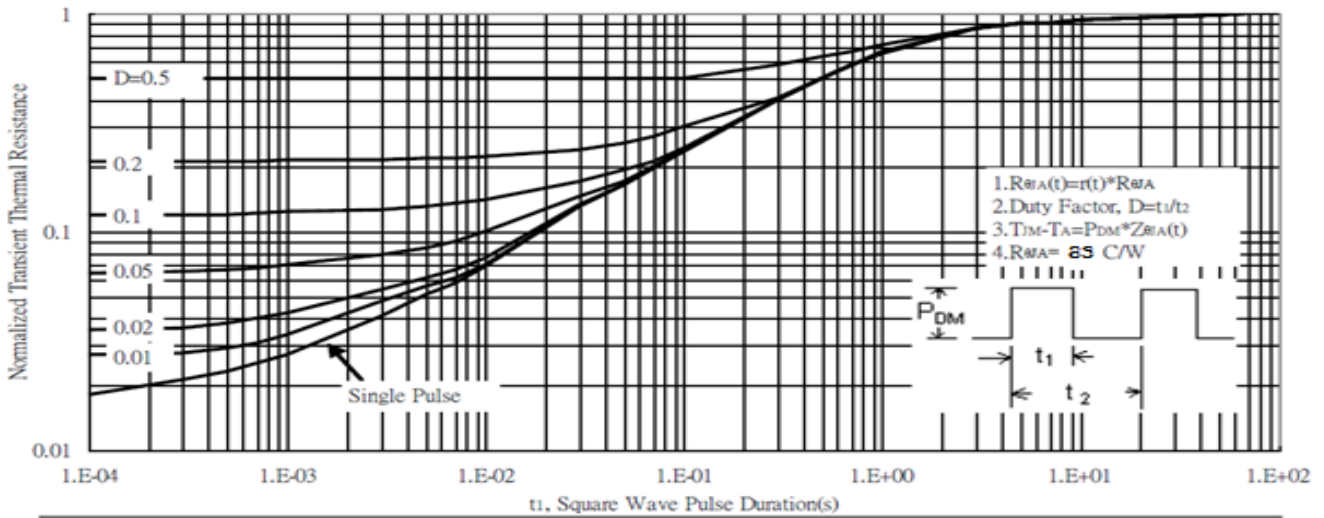


Fig.9 Normalized Maximum Transient Thermal Impedance

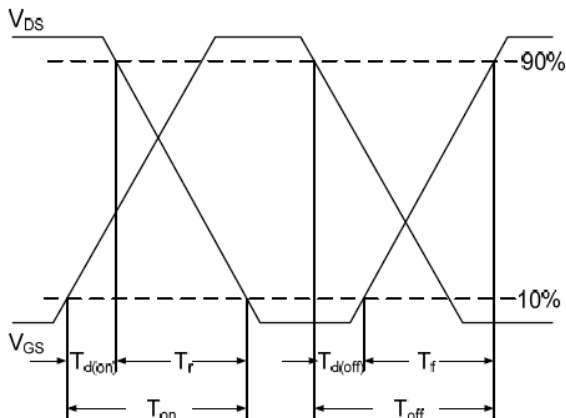


Fig.10 Switching Time Waveform

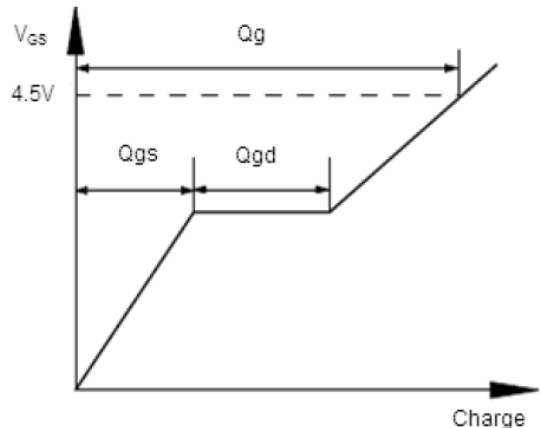
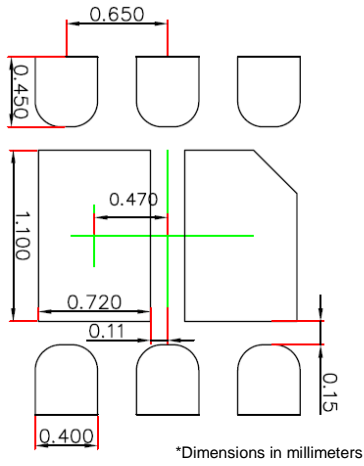


Fig.11 Gate Charge Waveform

**CHARACTERISTIC CURVE**



**Fig.13 Mounting Pad Layout**